

Search Notes

Application/Control No.

10/826,540

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

SCHREYER ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	3/12/2007	CH
455	404.1	3/12/2007	CH
455	574	3/14/2007	CH
455	11.1	3/12/2007	CH
455	414.4	3/12/2007	CH
455	521	3/12/2007	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
705	400	3/12/2007	CH
370	390	3/12/2007	CH
455	521	3/12/2007	CH
PG PUB		3/12/2007	CH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	3/12/2007	CH
Combibned Text	3/12/2007	CH
Talked to SPE	3/14/2007	CH